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EXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor SCHS028

CMOS Presettable **Divide-By-'N' Counter**

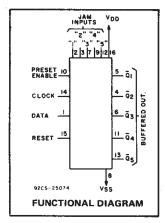
High-Voltage Types (20-Volt Rating)

CD4018B types consist of 5 Johnson-Counter stages, buffered Q outputs from each stage, and counter preset control gating. CLOCK, RESET, DATA, PRESET ENABLE, and 5 individual JAM inputs are provided. Divide by 10, 8, 6, 4, or 2 counter configurations can be implemented by feeding the $\overline{\Omega}5$, $\overline{\Omega}4$, $\overline{\Omega}3$, $\overline{\Omega}2$, $\overline{\Omega}1$ signals. respectively, back to the DATA input. Divide-by-9, 7, 5; or 3 counter configurations can be implemented by the use of a CD4011B to gate the feedback connection to the DATA input. Divide-by functions greater than 10 can be achieved by use of multiple CD4018B units. The counter is advanced one count at the positive clocksignal transition. Schmitt Trigger action on the clock line permits unlimited clock rise and fall times. A high RESET signal clears the counter to an all-zero condition. A high **PRESET-ENABLE** signal allows information on the JAM inputs to preset the counter. Anti-lock gating is provided to assure the proper counting sequence.

The CD4018B types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

Features:

- . 10 MHz (typ.) at $V_{DD} - V_{SS} = 10 V$
- Fully static operation
- 100% tested for quiescent current at 20 V
- Standardized, symmetrical output characteristics
- = 5-V, 10-V, and 15-V parametric ratings
- Maximum input current of 1 µA at 18 V over full packagetemperature range; 100 nA at 18 V and 25°C
- Noise margin (full package-temperature range) =
 - $\begin{array}{l} 1 \ V \ at \ V_{DD} = \ 5 \ V \\ 2 \ V \ at \ V_{DD} = \ 10 \ V \\ 2.5 \ V \ at \ V_{DD} = \ 15 \ V \\ \end{array}$
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices'

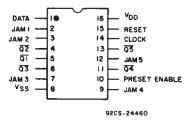


Applications:

- Fixed and programmable divide-by-10, 9, 8, 7, 6, 5, 4, 3, 2 counters
- Fixed and programmable counters greater than 10
- Programmable decade counters

CD4018B Types

- Divide-by-"N" counters/frequency synthesizers
- Frequency division
- Counter control/timers



TERMINAL DIAGRAM

Top View

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MAXIMUM RATINGS, Absolute-Maximum Values:
DC SUPPLY-VOLTAGE RANGE, (VDD)
Voltages referenced to V _{SS} Terminal)
INPUT VOLTAGE RANGE, ALL INPUTS
DC INPUT CURRENT, ANY ONE INPUT
POWER DISSIPATION PER PACKAGE (PD):
For $T_A = -55^{\circ}C$ to $+100^{\circ}C$
For T _A = +100°C to +125°C Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T _A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)
OPERATING-TEMPERATURE RANGE (T _A)
STORAGE TEMPERATURE RANGE (T _{stg})65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 \pm 1/32 inch (1.59 \pm 0.79mm) from case for 10s max

5.4

RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}$ C, Unless Otherwise Specified For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges.

CHARACTERISTIC	· · ·	VDD	Min.	Max.	UNITS
Supply Voltage Range (at T _A = F Temperature Range)		3	18	v	
Clock Input Frequency,	fCL	5 10 15		3 7 8.5	MHz
Clock Pulse Width,	t _W	5 10 15	160 70 50	·	ns
Clock Rise & Fall Time,	t _r CL,t _f CL	5 10 15	Unlimited		μs
Data Input Set-Up Time,	ts	5 10 15	40 12 16		ns
Data Input Hold Time,	t _H	5 10 15	140 80 60	_ _	ns
Preset or Reset Pulse Width,	tw	5 10 15	160 70 50	-	ns
Preset or Reset Removal Time		5 10 15	160 60 40	 	ns

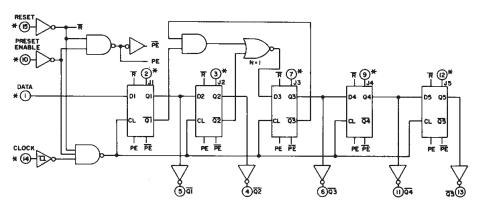


Fig. 1 – Logic diagram.

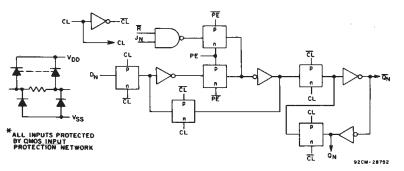
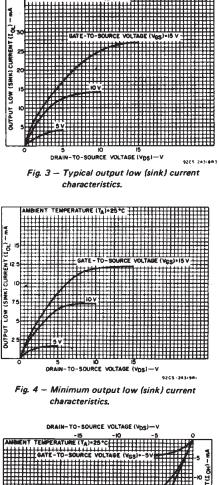


Fig. 2 - Detail of a typical stage.

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STATIC ELECTRICAL CHARACTERISTICS

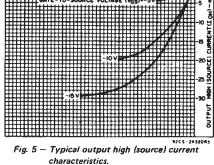
CHARAC- TERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (^O C)							U N I T
	vo	VIN	V _{DD}						+25		s
	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.	
Quiescent		0,5	5	5	5	150	150		0.04	5	
Device	-	0,10	10	10	10	300	300		0.04	10	μA
Current, I _{DD} Max.	_	0,15	15	20	20	600	600	-	0.04	20	ľ
	-	0,20	20	100	100	3000	3000	-	0.08	100	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	_	
IOL Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	
Output High	4.6	0,5	5	0.64	-0.61	-0.42	-0.36	-0.51	-1	-	m/
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	1
Current, I _{OH} Min.	9.5	0,10	10	-1.6	1.5	-1.1	-0.9	-1.3	-2.6	-	
OH MIN	13.5	0,15	15	-4.2	4	-2.8	-2.4	-3.4	-6.8	-	
Output Voltage:	-	0,5	5	0.05					0	0.05	
Low Level,	_	0,10	10	0.05				-	0	0.05	
VOL Max.	_	0,15	15	0.05				-	0	0.05	l v
Output		0,5	5	4.95				4.95	5	-	
Voltage: High-Level,		0,10	10	9.95				9.95	10	-	
V _{OH} Min.		0,15	15	14.95				14.95	15	-	
Input Low	0.5,4.5	-	5	1.5				-		1.5	
Voltage	1,9	_	10	3				_	-	3	
V _{IL} Max.	1.5,13.5	_	15	4				_	-	4	۱v
Input High	0.5,4.5		5	3.5			3.5	-	-		
Voltage, Vuu Min	1,9	_	10	7			7	-	-		
	1.5,13.5	_	15	11			11	-	—		
Input Current I _{IN} Max.	-	0,18	18	±0.1	±0.1	. ±1	±1	-	±10-5	±0.1	μA

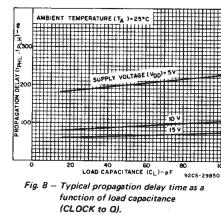


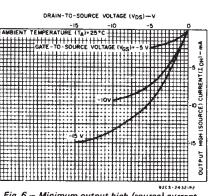
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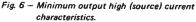
COMMERCIAL CMOS HIGH VOLTAGE ICs

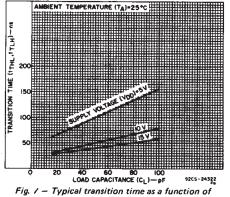
ENT TEMPERATURE (TA)-25 °C











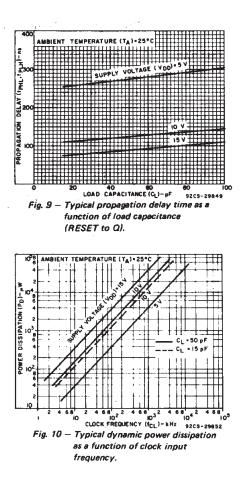
 / — Typical transition time as a function of load capacitance.

DYNAMIC ELECTRICAL CHARATERISTICS at $T_A = 25^{\circ}$ C, Input $t_r, t_f = 20$ ns,

CL = 50 pF, RL = 200 k Ω

CL - 50 pF, HL - 200 K12							
CHARACTERISTIC	TEST CONDITIONS			UNITS			
		V _{DD} (V)	Min.	Тур.	Max.	1	
CLOCKED OPERATION							
Proposition Dalay Times		5	_	200	400		
Propagation Delay Time;		10		90	180	ns	
tPLH, tPHL		15	-	65	130		
Transition Time;		5	_	100	200		
tTHL,tTLH		10	· —	50	100	ns	
STREATER		15	-	40	80		
Maximum Clock Input		5	3	6	_	MHz	
Frequency, f _{CL}		10	7	14	-		
		15	8.5	17	-]	
Minimum Clock Pulse Width,	1	5	-	80	160	ns	
		10	-	35	70		
tw		15	-	25	50		
Clearly Disc & Fall Times		5					
Clock Rise & Fall Time;		10 .]	μs			
t _r CL,t _f CL		15	1				
Minimum Data Input Set-Up		5	-	20	40		
-		10	-	6	12	ns	
lime. t _S		15	-	3	6		
Minimum Data Input Hold		5	-	70	140		
-		10	-	40	80	ns	
Time, ^t H	I	15	_	30	60		
Average Input Capacitance, C	Any Input		-	5	7.5	pF	
PRESET* OR RESET OPERA	TION						
Propagation Delay Time;		5	-	275	550		
Preset or Reset to $\overline{\mathbf{Q}}$		10	—	125	250	ns	
^t PLH ^{, t} PHL		15	—	90	180]	
Minimum Preset or Reset		5		80	160		
Pulse Width,		10	_	35	70	ns	
tw		15		25	50	1	
Minimum Preset or Reset		5	-	80	160		
Removal Time		10	—	30	60	ns	
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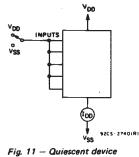
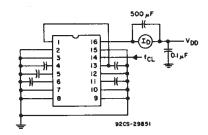


Fig. 11 — Quiescent device current test circuit.



* At PRESET ENABLE or JAM Inputs.

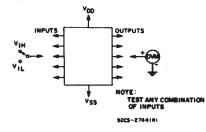
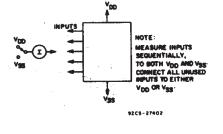


Fig. 12 - Input voltage test circuit.

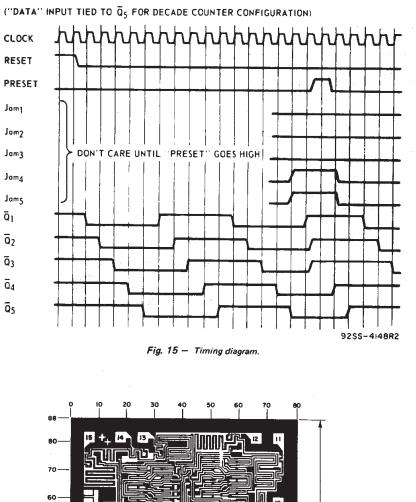


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Fig. 13 - Input current test circuit.

Fig. 14 – Dynamic power dissipation test circuit.



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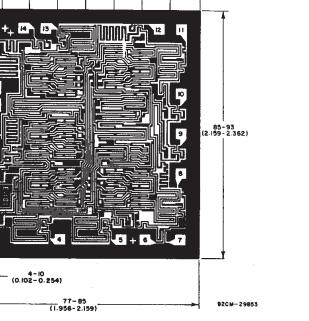
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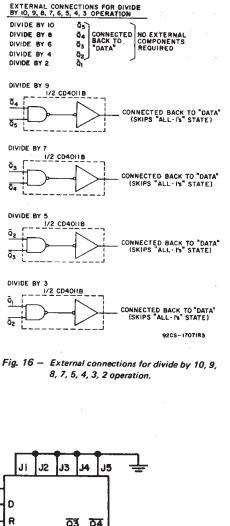
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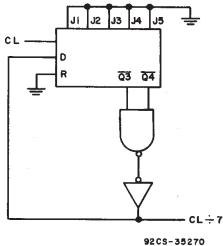
Chip dimensions and pad layout for CD4018B

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch) .











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